
Z8® MCU Test Mode



Application Note

June 1982

A large, stylized, black-and-white graphic of the word "Zilog". The letters are thick and blocky. The 'Z' is a simple rectangle with a diagonal cut. The 'i' has a dot above it. The 'l' is a simple vertical bar. The 'o' is a circle with a thick stroke. The 'g' has a circular bowl and a long, curved tail. The entire word is rendered in a high-contrast, bold font.

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This application note is intended for use by those with either a Z8601 or a Z8611 Microcomputer device. It is assumed that the reader is familiar with both the Z8 and its assembly language, as described in the following documents:

- Z8 Technical Manual (Reset Section) (03-3047-02)
- Z8 Family Z8601, Z8602, Z8603 Product Spec (00-2037-A0)
- Z8 Family Z8611, Z8612, Z8613 Product Spec (00-2038-A0)
- Z8 PLZ/ASM Assembly Language Programming Manual (03-3023-02)

This note briefly discusses the operation of Test Mode, which is a special mode of operation that facilitates testing of both Z8 devices that incorporate an internal program ROM (Z8601, Z8611). There are two problems associated with testing a Z8 with an internal program ROM; the solutions are presented below.

The first problem is: how can the device be tested with standard microprocessor automatic test equipment? To solve this problem, Test Mode causes the Z8 to fetch instructions from Port 1 while it is in the external Address/Data bus mode, instead of fetching instructions from the internal Program ROM. Diagnostic test routines are then forced onto this external bus from the test equipment in the same manner as with microprocessor testing.

The second problem is: since the Test Mode requires that Port 1 operate only in the Address/Data bus mode, how are the other Port 1 modes of operation tested? To solve this problem, an on-chip Test ROM is provided for execution while in Test Mode. The program in the Test ROM checks the other modes of Port 1: input, output, with handshake control, and without handshake control.

Figure 1 compares normal and Test Mode operations in the Z8. (In both normal and Test Mode, program execution begins at address 00CH.)

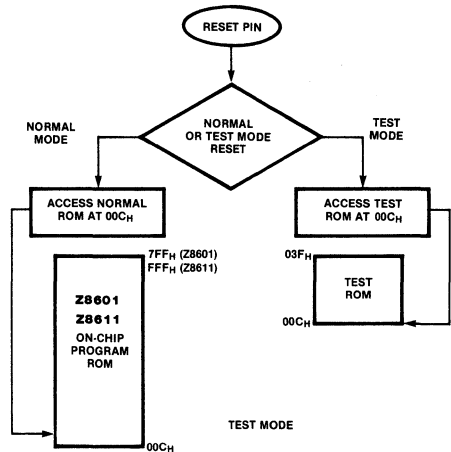
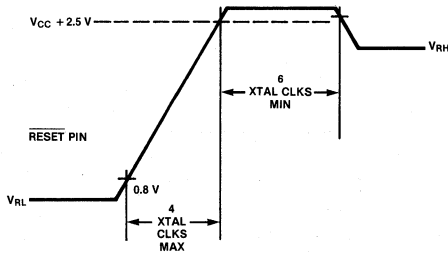


Figure 1. Comparison of Normal and Test Modes

Test Mode can be entered immediately after reset by driving the $\overline{\text{RESET}}$ input (pin 6) to a voltage of $V_{CC} + 2.5 \text{ V}$. (See the Reset section of the Z8 Technical Manual for a description of the Reset procedure.) Figure 2 shows the voltage waveform needed for Test Mode. After entering Test Mode, instructions are fetched from the internal Test ROM, which is programmed with Port 1 diagnostic routines. The Z8 stays in Test Mode until a normal reset occurs.



Note the maximum ramp for application of +7.5 VDC to RESET pin. After a minimum of 6 XTAL CLK cycles, the RESET voltage can be relaxed to V_{RH} .

Figure 2. Test Mode Wave Form

The program listing in the ROM is included at the end of this document. Program Listing A (Internal Test ROM Program) is mask programmed into the internal Test ROM of the Z8601. Program Listing B (External Test Program) is an example of a program that could be executed while in Test Mode. It was written as a compliment to the internal Test ROM program, to check the Port input and output functions. To test the other functions of the Z8, the user must execute other programs developed for testing.

The interrupt vectors in the Z8601 Test ROM point to the locations in external memory %800, %803, %806, %809, %80C, %80F. The interrupt vectors in the Z8611 Test ROM point to the locations in external memory %1000, %1003, %1006, %1009, %100C, %100F. This allows the external program to have a 2- or 3-byte jump instruction to each interrupt service routine.

Programs that are run in Test Mode can use an LDE instruction for accessing the Test ROM. The LDC instruction can be used for accessing the program ROM.

Program Listing A. Internal Test ROM Program

```

Z8ASM      4.0
LOC      OBJ CODE      STMT SOURCE STATEMENT

          1              ! Z8 TEST ROM ROUTINE FOR VERIFYING !
          2              ! PORT 1 I/O, WITH AND WITHOUT H.S. !
          3
          4
          5 TESTROM MODULE
          6
          7
          8 $SECTION PROGRAM
          9 $ABS 0
         10      INTERNAL
         11      RUPT_VECTOR ARRAY [6 WORD]:=
P 0000 0800 0803
P 0004 0806 0809
P 0008 080C 080F
         12      [%800 %803 %806 %809 %80C %80F]
         13 $SDEFAULT
         14
         15
         16 INTERNAL
         17 TEST
P 000C
         18 PROCEDURE ENTRY $ABS %00C
         19
         20      LD P01M #%96      ! P1&P0=EXT MEM,STK=IN,NORMAL !
         21      JP EXT          ! JUMP TO EXTERNAL TEST CODE !
         22 START1: LD P01M R9      ! START OF P1 I/O TEST !
         23      LD P3M R10       ! SET H.S.& P2 PU ACTIVE !
         24      LD R4 %E3        ! TEST RDY=1,DAV=1 !
         25      LD @R13 R14      ! WRITE PORT !
         26      COM @R13         ! WRITE PORT !
         27      LD R5 %E3        ! TEST RDY=0,DAV=1 !
         28      LD R6 @R11       ! READ PORT & STUFF DATA !
         29      LD R7 @R11       ! DITTO !
         30      LD R8 %E3        ! TEST RDY=1,DAV=1 !
         31      LD P01M R12     ! CONFIGURE FOR EXT !
         32      JP VERIFY1      ! JUMP TO VERIFY ROUTINE !
         33

```

Program Listing A. Internal Test ROM Program (continued)

```

P 0029 B9 F7      34 START2: LD P3M R11      ! START TEST NO H.S. !
P 002B 99 F8      35          LD P01M R9      ! SET P1 TO INPUT !
P 002D 1E          36          INC R1          ! READ & WRITE P1 AS INPUT !
P 002E F9 F8      37          LD P01M R15     ! SET P1 TO OUTPUT !
P 0030 1E          38          INC R1          ! READ & WRITE P1 AS OUTPUT !
P 0031 98 E1       39          LD R9 %E1       ! SAVE RESULTS IN R9 !
P 0033 C9 F8       40          LD P01M R12     ! P1&P0=EXT,STK IN,NORMAL !
P 0035 8D 086D    41          JP VERIFY2      ! JUMP TO VERIFY #2 ROUTINE !
P 0038            42 END TEST

```

Program Listing B. External Test Program

```

                                47 INTERNAL
                                48 SETUP
P 0800            49 PROCEDURE ENTRY $ABS %800
                                50
P 0800 8D 0800    51 VECT1:  JP VECT1
P 0803 8D 0803    52 VECT2:  JP VECT2
P 0806 8D 0806    53 VECT3:  JP VECT3
P 0809 8D 0809    54 VECT4:  JP VECT4
P 080C 8D 080C    55 VECT5:  JP VECT5
P 080F 8D 080F    56 VECT6:  JP VECT6
                                57
P 0812 8F        58 EXT:    DI
P 0813 31 00     59          SRP #%00
P 0815 2C FF     60          LD R2 #%FF      ! INITIALIZE P2 !
P 0817 3C FF     61          LD R3 #%FF      ! DITTO !
P 0819 E6 F6 FF 62          LD P2M #%FF      ! SET P2 TO INPUT !
P 081C 4C 88     63          LD R4 #%88      ! SET P2<>P1 MUX,P3 GRP B MUX !
                                64          ! ALSO DUMMY ADDRS HIGH BYTE !
P 081E 5C 00     65          LD R5 #%00      ! DUMMY ADDRS LOW BYTE !
P 0820 9C 86     66          LD R9 #%86      ! P1 OUTPUT MODE VALUE !
P 0822 AC 39     67          LD R10 #%39     ! R10 SETS H.S.MODE & P2 PULLUPS
P 0824 BC 02     68          LD R11 #%02     ! R11 POINTS TO P2 FOR PASS1 !
P 0826 CC 96     69          LD R12 #%96     ! R12 SETS P01M TO EXT MEM,ETC.
P 0828 DC 01     70          LD R13 #%01     ! R13 POINTS TO P1 FOR PASS1 !
P 082A FC 86     71          LD R15 #%86     ! SAME AS R9 !
P 082C EC AA     72          LD R14 #%AA     ! DATA LOADED TO TEST PORT !
P 082E E6 10 10 73          LD %10 #%10     ! RDY/DAV RESULT PASS 1 !
P 0831 E6 11 40 74          LD %11 #%40     ! DITTO !
P 0834 8D 0012   75          JP START1      ! END SETUP--JUMP TO TEST START
P 0837            76 END SETUP
                                77
                                78
                                79 INTERNAL
                                80 VERIFY
P 0831            81 PROCEDURE ENTRY $ABS %831
                                82
                                83
P 0831 DC 02     84 VERIFY1:LD R13 #%02     ! R13 POINTS TO P2 FOR PASS2 !
P 0833 BC 01     85          LD R11 #%01     ! R11 POINTS TO P1 FOR PASS 2 !
P 0835 E6 F6 00 86          LD P2M #%00     ! SETS P2 FOR OUTPUT !
P 0838 66 E4 50 87          TCM R4 #%50     ! FROM HERE TO THERE WE VERIFY !
                                88          ! TEST RESULTS FOR I/O WITH H.S.
                                89          ! BOTH PASS 1&2 !

```

Program Listing B. External Test Program (continued)

```

P 083B ED 0880 90 JP NZ FAIL
P 083E 64 10 E5 91 TCM R5 %10
P 0841 ED 0880 92 JP NZ FAIL
P 0844 74 11 E5 93 TM R5 %11
P 0847 ED 0880 94 JP NZ FAIL
P 084A A6 E6 AA 95 CP R6 #AA
P 084D ED 0880 96 JP NZ FAIL
P 0850 A6 E7 55 97 CP R7 #55
P 0853 ED 0880 98 JP NZ FAIL
P 0856 66 E8 50 99 TCM R8 #50
P 0859 ED 0880 100 JP NZ FAIL
P 085C A6 E9 86 101 CP R9 #86 ! IS THIS PASS1? !
P 085F E6 10 40 102 LD %10 #40 ! RDY/DAV RESULT PASS 2 !
P 0862 E6 11 10 103 LD %11 #10 ! DITTO !
P 0865 9C 8E 104 LD R9 #8E ! P1 IS GOING TO BE AN OUTPUT !
P 0867 6D 0012 105 JP EQ START1 ! PASS1 SUCCESSFUL--TRY PASS2 !
P 086A 8D 0029 106 JP START2 ! PASS2 SUCCESSFUL--TEST NO H.S.
P 086D A6 E9 57 107 VERIFY2:CP R9 #57 ! CHECK RESULT OF I/O NO H.S.TES
108
P 0870 6D 0890 109 JP EQ PASS
P 0873 110 END VERIFY
111
112
113 INTERNAL
114 TPASS
P 0890 115 PROCEDURE ENTRY $ABS %890
116
0890 8B FE 117 PASS:JR PASS
118
0892 119 END TPASS
120
121
122
123 INTERNAL
124 TFAIL
0880 125 PROCEDURE ENTRY $ABS %880
126
127
0880 8B FE 128 FAIL:JR FAIL
129
0882 130 END TFAIL
131
132 END TESTROM

```

Assembly complete

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